

IECEE

OD-2018-Ed.9.1

OPERATIONAL & RULING DOCUMENTS

**IECEE GROUPS: WORKING GROUPS
AND TASK FORCES**

OD-2018-Ed.9.1

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IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components

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IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components

BOA (Board of Appeals)

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
BOA (Board of Appeals)	CMC	<p>Joe GRYN (UL (CA)), Chairman</p> <p><u>Members:</u></p> <p>Paul MOLISKI (ITS USA) Yoji ONO (JQA) Michel BRENON (LCIE) Shawn PAULSEN (CSA International)</p> <p><u>Deputies:</u></p> <p>Trond SOLLIE (NEMKO) Wolfgang KREINBERG (TUV SUD PS) Ted GAERTNER (DEKRA Certification B.V.) Chinese MB nomination</p>	<p>a) to recommend a solution to any dispute referred to it with regard to the application of these basic rules, and</p> <p>b) to recommend actions to be taken against NCBs and CBTLs on complaints received regarding potential infringements to the Rules that could compromise the credibility of the IECEE Schemes.</p> <p>c) to report to the CMC, for appropriate action, any observations relating to the technical content of the standards accepted for use in the IECEE and their applications, that has become evident when investigating a dispute</p>	

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PAC (previously AAG)

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
PAC	CMC	P.de RUVO (IECEE Secretary) - Chair J. XIE (CNCA – Vice Chairman) Jing BIAN (CQC) Gerhard DREGER (VDE) Joe GRYN (UL (CA)) Masahiro SATO (JET) Trond SOLLIE (NEMKO) Wolfgang KREINBERG (TUV PS) Ted GAERTNER (DEKRA Certification B.V.) Jung Sup KIM (KTL) Bill LOWE (CSA International) John QUIGLEY (ITS NA) Mika RICHARDT(SGS Fimko) Michael HINGOTT (TUV SUD PS) Observer as member of PAAG: Craig DIACK-EVANS (ASTA)	<ul style="list-style-type: none"> •To monitor the Peer Assessment Program •To determine common understanding of ISO/IEC Guide 65 and ISO/IEC 17025 •To clarify matters pertaining to Certification issues •To evaluate the Assessment Reports of candidate NCBs and CBTLs and make recommendations to the CMC •To support and contribute as lecturers at the IECEE Lead and Technical Assessor training courses 	
PAC SG1 (previously WG 11) "PEER ASSESSMENT DOCUMENTS"		P. de RUVO (Convenor) Trond SOLLIE (NEMKO) Alberto PEDERNESCHI (IMQ) Joe GRYN (UL (CA))	Maintenance of NCB and CBTL assessments reports	

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CAG (Chairman's Advisory Group)

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
CAG (Chairman's Advisory Group)	CMC	Invitees are determined by the IECEE Chairman following specific topics for which the Chairman needs advice.	To advise the IECEE Officers on issues that are decided by the Chairman and tabled at each meeting.	February 25 th , 2004

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POLICY & STRATEGY FORUM

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
Policy & Strategy Forum	CMC	<p>G. Fredriksson (Convenir) P. de RUVO (Secretary)</p> <p>Senior Conformity Assessment Delegate Members Joe Gryn (UL (CA)) Alternate Shawn Paulsen (CSA International) Du Chunjing (CNCA) Alternate: Bian Jing (CQC) Gerhard Dreger (VDE) Jukka Vuorinen (SGS Fimko Ltd) Michel Brenon (LCIE) Giancarlo Zappa (IMQ) Toshiyuki Nawata (JISC) Mike Lawson (ASTABEAB) Steven Margis (UL (US)) Alternate: David Surber (TUV Rheinland) Gitte SCHJOTZ (UL Demko) Franklin Willemstein (DEKRA Certification B.V.) Fredrik Wennersten (Intertek SEMKO) Daniel Goldstein (SII) Yoji Ono (JQA) Ari Ugayama (JISC METI)</p> <p>Senior Industry Delegate Members: Saeed Ahmad (Christie Digital Systems, Inc.) YU Zida (China Haier Group Corporation) Uwe Kampet (BSH) Alternate: Jörg Hartge (ZVEI) Jari Yli-Juuti (ABB Finland) Jean-Pierre Isnard (FIEEC) Giovanni Cassinelli (Bticino S.p.A) Alternate Matteo Gavazzeni (GEWISS S.p.A) Toshiyuki Kajiya (Panasonic) Bob Taylor (Coutant Lambda Ltd.) Richard Pescatore (USNC/IECEE) Alternate: John Mahanna (IBM) Tim Duffy (Rockwell Automation)</p>	<p>To identify market needs and propose IECEE market solutions to meet those needs and to maintain high quality third party conformity assessment principles.</p> <p>To propose mechanisms for ensuring that the IECEE Conformity Assessment solutions are recognized as the basis for certification and acceptance in regulated markets world wide in a timely way.</p> <p>To develop a framework or road map for the development of conformity assessment solutions within the IECEE scheme including such elements as:</p> <p>a) Type Test Certification b) Access to the marks of other Certification Bodies c) Full Certification Scheme. d) IECEE Conformity Assessment solutions that facilitate market access and relevance, including SDoC.</p>	2008-06-09



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		Wim Honig (Philips) Yehuda Haiman (The metal, Electrical & Infrastructure Industries Association) Thommy Frantzén (Electrolux)		
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CMC - WORKING GROUPS

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
CMC-WG 2 "Business Development"	CMC	Pierre de RUVO (Convenor) Toshiyuki NAWATA (JISC) Kenji FUKASAWA (JQA) Ari Ugayama (JISC METI) Kurt HEINZ (TUV RH JP) Uwe KAMPET (GERMAN-NC/IECEE) Representative ASIA-PACIFIC Trond SOLLIE (NEMKO) Jukka VUORINEN (SGS Fimko) Yaacov WACHTEL (SII) Steven MARGIS (UL (US)) Fulvio Giorgi (IMQ) Ron Collis (Rockwell Automation) Nick Maalouf (QPS) Shawn Paulsen (CSA International) Tim Duffy (Rockwell Automation) Knut Boettcher (TUV SUD PS)	To explore further the market needs focusing around the electrotechnical sector (i.e. EMC, etc.) as well as other fields of interest for the industry. To analyze and survey any possible business development services that could be of interest for the IECEE	To be determined
Sub-Working Group 2-A "Smart Grid"	CMC-WG 2	Steven MARGIS (UL – Convenor) Ron Collis (Rockwell Automation) Shawn Paulsen (CSA International) Fulvio Giorgi (IMQ) Wolfgang Kreinberg (TUV SUD PS) Jens Hempel (TÜV RH Japan)	To explore potential and yet practical conformity assessment applications in the field of "Smart Home", "Smart Building" and "Smart Industry (Factory)".	To be determined
Sub-Working Group 2-B "Industrial Automation"	CMC-WG 2	Ron Collis (Rockwell Automation - Convenor) Steven MARGIS (UL (US)) Kurt HEINZ (TUV RH JP) Tim Duffy (Rockwell Automation)	To follow up the work undertaken by TC 65 and the outcome of CDV IEC 61010-2-201 that is in preparation. In case of a positive vote it is expected that the publication of IEC 61010-2-201 be effective in early 2012. To draft the Test Report Form in due time before the publication so as the IECEE System could launch the new services	To be determined



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
			under the Product Category "Industrial Automation" INDAT.	
Sub-Working Group 2-C "Energy Efficiency"	CMC-WG 2	Kurt HEINZ (TUV Rh JP - Convenor) , Knut Boettcher (TUV SUD PS), Shawn PAULSEN (CSA International) Ilan Carmit (SII) Jens Hempel (TÜV RH Japan) Jon Ivar Tidemann (Nemko)		
CMC-WG 3 "MTL"	CMC	Michel BRENON (LCIE- Convenor) Joe GRYN (UL (CA)) Fulvio GIORGI (IMQ) Randolf KELLER (TÜV Rh Jap) Tuneyuki SATO (JET) Michael HINGOTT (TÜV Süd P.S.) Robin TIZZARD (BSI) Richard PESCATORE (USNC/IECEE) Jim CONROY (ITS Boxborough) Alternate: Craig DAVENPORT (ITS) Jola Wroblewska (UL (US)) Zvi Egozi (SII) Tim Duffy (Rockwell Automation) Thomas Fischer (Siemens AG)	To analyse and develop procedures related to the Manufactory Testing Laboratories programme.	September 19th, 2002, Geneva, IECEE Secretariat, Salle Bois
CMC-WG 4 "Components Acceptance"	CMC	Jola WROBLEWSKA (UL-Convenor) Joe GRYN (UL (CA)) Bill FISKE (USNC) Mohd Nazif (SIRIM) Ilan Carmit (SII) Mr. Ray Jefferis (ASTABEAB)	To identify component standards	WG disbanded and transfer of terms of reference and allocated assignments into WG 5 "Component Recognition"



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
CMC-WG 5 "Components Strategic"	CMC	Paul Moliski (Convenor) (ITS U.S.A.) Klaus KRESS (VDE – DE MB) Marvin MAALOUF (ENTECLA – CA MB) Joe GRYN (UL (CA)) Fulvio GIORGI (IMQ - IT MB) Jola WROBLEWSKA (UL (US)) – USNC MB) Bill FISKE (ITS N.A. – USNC MB) Jean LANZO (LCIE - FR MB)) Ted Gaertner (DEKRA CERTIFICATION B.V.) Bill Burr (CSA International)	<ol style="list-style-type: none"> Examine the current operational practices in the CB Scheme with respect to acceptance of components. <ol style="list-style-type: none"> Review the results of the survey carried out by the CMC-WG Component. Review the newly developed Guide converted into a Current Decision, Annex 1 of OD-2022, that has replaced Decision 1D115 on Acceptance of Components, to identify all situations in which components evaluated in an end-product by the issuing NCB may be not accepted by the recognizing NCB. Carry out a strategic analysis of the current and future needs of the CB Scheme and the FCS with respect to acceptance of components. Develop a proposal or proposals to substantially improve the acceptance of components, with particular emphasis on the needs and expectations related to FCS. 	To be determined
CMC-WG 6 "IECEE International Mark"	CMC	Maarten VAN DER DUSSEN (Convenor) Roy Jacobi (SAI Global) Jean-Louis ROBERT (CANADIAN-NC/IECEE) Gösta FREDRIKSSON (SEMKO) Rob FENNELL (CSA) Jonathan KOTRBA (TUV N.A.) Jola WROBLEWSKA (UL (US)) William H. JOHNSON (USNC/IECEE)	To explore further the idea of an International Mark monitored by the IEC.	WG disbanded following 2002 CMC Meeting, task transferred to CAB WG 7
CMC-WG 7 "Interrelation between NCBs and CBTLs"	CMC	Donald A. MADER (Convenor) Joe GRYN (UL (CA)) Wolfgang KREINBERG (TUV PS)	To update the “examples of NCBs/CBTLs combinations” and provide additional clarifications.	WG Disbanded 2002-06



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
CMC-WG 8 “Acceptance of CB and CB-FCS Certificates”		Ron Collis (Rockwell Automation) (Convenor) Tim Duffy (Rockwell Automation) Uwe Kampet (BSH) Bob Taylor (Coutant Lambda Ltd.) Jean-Pierre Isnard (FIEEC) Bill Fiske (ITS N.A. - USNC MB) Vladimir Filiac (EZU) Fredrik Wennersten (Intertek Semko) Shawn Paulsen (CSA International) Toshiyuki Kajiya (Panasonic)	1. To propose to the IECEE CMC and to the IECEE Policy Forum some recommendations - in a guideline for example- , in line with the ethics, in order to help manufacturers and certifiers to protect their products/activities, when they are faced with any unfair competition of manufacturers producing counterfeited products, which are certified in the context of IECEE System. 2. To do that, the WG shall carry out the necessary research. Methods of work should include polling of manufacturers and Certification Bodies in a formal manner to determine the market need for the IECEE to provide any measure of counterfeiting protection, and researching the legal ramifications of proposed options.	
CMC-WG 9 “TRF”	CMC	Jola WROBLEWSKA (UL) (Convenor) Mauro CASARI (IMQ) Klaus KRESS (VDE)) Richard PESCATORE (USNC/IECEE) Ralf Knapp (TUV Rh Japan) Bill Lowe (CSA)	To deal with matters pertaining to TRFs	Task completed 2001
CMC-WG 10 "Maintenance of the IECEE Rules and Operational Documents"	CMC	Pierre de RUVO (IECEE) Gosta FREDRIKSSON (IECEE Chairman) Jun XIE (IECEE Vice-Chairman) Fritz BEGLINGER (Treasurer IECEE) Jola Wroblewska (UL (US)) Trond SOLLIE (NEMKO) Kurt HEINZ (TÜV Rh JAPAN) Kiyoto MITSUI (JISC) Gerhard DREGER (VDE) Joe GRYN (UL (CA)) Alberto PEDERNESCHI	To Review and update the IECEE Basic Rules, IECEE 01, the Rules of Procedure, IECEE 02, and those Operational Documents that are not under the terms of reference of existing IECEE Working Groups. To Review Current Decisions that are not within the scope of existing IECEE Working Groups and to	



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
		(IMQ) Michael Hingott (TUV SUD PS) Yaacov WACHTEL (SII)	incorporate them in the IECEE Rules, IECEE 01, the IECEE Rules of Procedure, IECEE 02 or Operational Documents as appropriate. To Refer Current Decisions that are within the scope of existing IECEE Working Groups to the appropriate WGs for incorporation into the appropriate Operational Document(s)	
Sub-Working Group 10-A "Current Decisions"	CMC-WG 10	Pierre de RUVO (IECEE) Trond SOLLIE (NEMKO) Kurt HEINZ (TÜV Rh JAPAN) Joe GRYN (UL (CA))		
CMC-WG 12 "Acceptance and Use of IEC Standards"		Gerhard DREGER (VDE) (Convenor) Johnny Jensen (UL (Demko)) Bill Fiske (I.T.S NA) Joe Gryn (UL (CA)) Osmo Väyrynen (SGS Fimko) Donald Mader (Observer) Masahiro Sato (JET) Tshepo Motsoane (SABS)	To determine the mechanisms of seeking scope extension to new published IEC standards, Editions, Amendments and responsibilities from NCBs when they seek scope extension of new published standards	
CMC-WG 13 "FCS Operations"			Disbanded	
CMC-WG 14 "Public Information"	CMC	Kurt K. HEINZ (TUV RH JP) (CONVENOR) Bill BRYANS (BryBrook Consulting) Michel BRENON (LCIE) Alberto PEDERNESCHI (IMQ) Japan Richard PESCATORE (USNC/IECEE)	To Consider the Japanese proposal in light of the real market needs and propose a database that in addition to providing selected information related to the content of issued CB Test Certificates could also consider the issue pertaining to the National Differences	
CMC-WG 15 "Database"	CMC	Paul TAN (PSB) (CONVENOR) Wei CHEN (CQC) Yun ZHANG (CQC) Weng-Hoe CHONG (PSB) Len FLEMING (BEAB) Jola WROBLEWSKA (UL (US))	To study the feasibility of a master searchable database that would have a global use within the IECEE operations and administration	



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
		Bill BRYANS (BryBrook Consulting)		
CMC-WG 16 “Satellite Laboratories”	CMC	Steven MARGIS (UL) (CONVENOR) Joe GRYN (UL (CA)) Michael HINGOTT (TUV PS) Michel BRENON (LCIE) Bill FISKE (ITS-USA) Johnny JENSEN (UL (Demko))	To develop a Draft OD that integrates the various comments and concerns as well as the impact measurements.	
CMC-WG 17 “PV Manufacturers Assessment, Surveillance and Audit requirements “	CMC	L. Ji, UL Inc. (Convenor) K. Shirai (JET) W. Herrmann (TUV RH) A. Pederneschi (IMQ) Mr. Arnd Roth (VDE) Soo-Hyun PAIK (KTL) Philippe GUILLON (LCIE)	To develop the required elements for initial assessment, continuing surveillance and audit for manufacturers producing photovoltaic equipment under the IECEE CB Scheme category for photovoltaic equipment.	WG disbanded and assigned to FIC after the 2008 CMC Meeting
CMC-WG 20 “Hazardous Substances”	CMC	Tim Duffy (Rockwell Automation) (Convenor) Ron Collis (Rockwell Automation) Dr. Ma Qiju (CQC) Alternate : Ms. Hu Nan (CQC) Michel Brenon (LCIE) Uwe Kampet (GERMAN-NC/IECEE) Karl Sander (TÜV RH DE) Toshiyuki Kajiya (JISC) Ted Gartner (DEKRA CERTIFICATION B.V.) Calogero Lana (SGS Cebec) Steven MARGIS (UL (US))	<ul style="list-style-type: none"> • To track the current status of work coming out of TC 111, Environmental, to ensure that Standards coming out of TC 111 are relevant to the market place. This will be accomplished via WG 20 liaison status. • To research Industry needs for the potential service offering for REACH. • To review the new Hazardous Substance requirements being issued by Countries and the potential use of the IECEE STR in those countries. • To Promote the IECEE STR and RoHS activity within the IECEE to the wider Industry and in particular to SMEs (Small to Medium Enterprises). • To work with WG 25 on the promotional activities of Hazardous Substance STR's. 	2006-11-27
CMC-WG 21 “CBTC Recognition Process”	CMC	Gunsimar Paintal, Underwriters Laboratories of Canada Inc. (Convenor) Michel Brenon (LCIE)	<ul style="list-style-type: none"> • evaluate the elements that are currently leading to a slowing down of the Recognition process • determine and 	WG disbanded following 2010 CMC Meeting,



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
			<p>propose the corrective actions that could overcome the reason of the slow down</p> <ul style="list-style-type: none"> · recommend the necessary actions to improve the “Recognition” process of CB Test Certificates by Members NCB without unnecessary 	
ad hoc CMC-WG 22 “Validity of IECEE Certificates”	CMC	Kurt Heinz, TUV RH JP (Convenor) Alberto Schiuma (IRAM) Jason Cooke (SAI Global) Bill Bryans (BryBrook Consulting) Fulvio Giorgi (IMQ) Toshiyuki Kajiya (Panasonic) Isaac Thabo Mabena (SABS) Alternate: David Surber (TUV RH NA)	Analysis of the implications for the parties regarding the introduction of validity of CB Test Certificates and the most appropriate mechanism to establish a term of validity for CB Test Certificates.	WG disbanded following 2010 CMC Meeting,
CMC-WG “IECEE MEE Task Force”	CMC	Alfred Dolan (convenor) Irina Antonov (SII) Michel Brossoit (CSA International) Ted Gaertner (CTL ETF 3 Convenor) Steli Loznen (Convenor IEC/TC62/SC62A/WG17) Richard J. Markle (Philips Medical Systems) Steve McRoberts (UL Europe) Joseph Murnane (UL (US)) Massimo Polignano (ESAOTE S.p.A.) Geri Richter (Geri-Con) Martin Schneeberg (TUV SUD) Michael Sippl (TUV SUD / IEC SC62A) Paul Tan (TUV SUD PSB) Jola Wroblewska (WG 9 Convenor) Mauro De Angiolini (IMQ) Thomas Storch (Siemens) Michel Genuer (GE France regulatory safety group) Dale Hallerberg (TÜV Rheinland North America)	<p>To establish a consensus with methods acceptable to determine compliance with all the relevant clauses (related to ISO 14971) of IEC 60601-1 Ed. 3.</p> <p>To develop a Guideline document & Work Instruction on how to implement the relevant clauses (related to ISO 14971) of IEC 60601-1 Ed. 3.</p> <p>To develop a Checklist aiming at assisting ME Industry, Official Authorities and Stakeholders around the world, Testing Laboratories and Certification Bodies to properly deal with Risk Management.</p> <p>To develop an addendum to the Test Report Form IEC 60601-1 to cover the overall requirements pertaining to ISO 14971.</p> <p>To set up the content of possible trainings to cover Risk Management issues.</p> <p>To be the Advisory Group</p>	



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
			on common understanding of ISO 14971 related to IEC 60601-1.	
CMC-WG 23“ Counterfeit”	CMC	Jean-Pierre ISNARD (convenor) Richard Pescatore (USNC IECEE) Don Mader (UL (US)) Toshiyuki Kajiva (Panasonic) Yu Zida (Haier) Mike Lawson (Intertek) Vladimir Filiac (EZU) Luca Taglioretti (IMQ) Katharina Seidel (TUV RH DE)	Disbanded CMC decision 065/2011	
CMC-WG 24 “Infringement”	CMC	Joe Gryn (Convenor) Trond Sollie (NEMKO) Ms. Bo Yumin (CNCA) Richard Pescatore (USNC IECEE) Ms P Mazibuko (NRCS) M. Brénon (LCIE) Yoji Ono (JQA) Ted Gaertner (DEKRA CERTIFICATION B.V.)	1. Identify the various forms of infringements based on the experiences of the IECEE Secretariat and the Members of WG 24 as well. 2. Explore the infringement issues and propose appropriate administrative measures for the IECEE, including the related responsibilities. 3. Draft a set of rules to consistently manage infringements within the IECEE.	
CMC-WG 25 Marketing	CMC	Ted Gaertner (DEKRA CERTIFICATION B.V.) (Convenor) Gabriela Ehrlich (IEC Head of the Marketing and Communication Department) Gitte Schjøtz (UL (Demko)) Kurt Heinz (TÜV Rheinland Japan) Trond Sollie (Nemko) Vladimir Filiac (EZU) Toshiyuki Kajiya (Panasonic)		

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FCS – TASK FORCES and WORKING GROUPS

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
FCS TASK FORCE "A"	CMC	Past IECEE Secretary	To develop <ul style="list-style-type: none"> ◆ Questionnaire to determine what NCBs are interested in participating in the CB-FCS 	ON HOLD
FCS TASK FORCE "B"	CMC	Pierre de RUVO (Convenor)	To develop <ul style="list-style-type: none"> ◆ Mfr Conformity Assessment Procedures ◆ Mfr Q.S. Questionnaire ◆ Audit Report Form 	ON HOLD
FCS TASK FORCE "C"	CMC	Don MADER (Convenor)	To develop <ul style="list-style-type: none"> ◆ CAC ◆ FCS Agreement ◆ Rider to Agreement 	ON HOLD
FCS TASK FORCE "D"	CMC	Trond SOLLIE (Convenor)	To develop <ul style="list-style-type: none"> ◆ Application Form ◆ Audit Check List 65 ◆ Audit Check List 25 ◆ Template Ass. Rep. ◆ Certificate for accepted NCBs 	ON HOLD
WG 2 REVISION IECEE 03	EVA-G	P. de RUVO (Convenor) P. LEONG (PSB) A.PEDERNESCHI (IMQ) J. SJÖBERG (SEMKO) T. SOLLIE (NEMKO) J. WROBLEWSKA (UL (US))	To revise the Rules of Procedure of the CB-FCS	Pending the issue from the WG "FCS Operations"
WG 1 Peer Assessment Guidelines	EVA-G	A. PEDERNESCHI (Convenor) A.PEDERNESCHI (IMQ) T. SOLLIE (NEMKO) B.WINTHER (DEMKO)	To produce Guidelines pertaining to Peer Assessment activities	Permanent review

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CTL WORKING GROUPS and TASK FORCES

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
CTL-WG 1 Accuracy/ Uncertainty		J. Hall (UL Inc. – Convenor) D. BARBINI (CSA Int.) M.LESCURE (LCIE) M. HINGOTT (TUV PS) J.OLOGBOSERE (TUV RH JP) M. ANDERSEN (NEMKO) B. JANSSON (SEMKO) B.BREITENBACH (VDE) J.O. STILLING (INTERTEK) S. NONAKA (JAB) Z. WANG (CQC) R. FLORCZYK (UL (US)) M. RUZZA (IMQ) H. SCHORN (Institute for International Product Safety GmbH)	To develop an IECEE position paper detailing the rationale why accuracy is the preferred approach for the IECEE Laboratories. To develop a procedure/guide to be used by all CBTLs so as to show accreditors and peer assessors that the IECEE is following a consistent approach when the expression of Uncertainty Measurement is absolutely necessary, with regard to clause 5.4.6 of ISO/IEC 17025.	Revised draft for CTL agenda by March 2002
CTL-WG 2 PTP	CTL	H. Bachl (CTI, Convenor) M. Sato (Convenor ETF 1) M. Hingott (Convenor ETF 2) T. Gaertner (Convenor ETF 3) A. Bretz (Convenor ETF 4) E. Parma (Convenor ETF 5) JP. Barbier (Convenor ETF 10) Mr. L. Ji (Convenor ETF 9) D. BARBINI (CSA Int.) X. Mo (CQC) Z. Egozi (SII) J. Pierce (ITS USA) I. Flemming (IFM) T. Wong (Convenor ETF 11) Ms. Zhu (Convenor ETF 6) U. Krischke (Convenor ETF 12) J. Hall (Convenor WG1) C. Swee-Gee (Convenor WG 3) K. Iwasaki (UL (US))		On Going
CTL-WG 3 Editing Group	CTL	C. Swee-Gee (PSB - Convenor) Hubert BACHL (CTI) Marc LESCURE (LCIE) Arkadiusz SALWA (UL (US)) Roland HERRMANN (Dekra Testing and Certification GMBH)	To review the CTL Decisions sheets and to coordinate with the ETFs on the wording to be used.	On Going
CTL-WG 4		E. Parma (Convenor)		On Going



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
Coordination		<p>M. Sato (Convenor ETF1) M. Hingott (Convenor ETF2) T. Gaertner (Convenor ETF3) A. Bretz (Convenor ETF 4) Ms. Zhu (Convenor ETF6) Mr. L. Ji (Convenor ETF 9) H. Bachl (Convenor ETF 7 ad interim) J.P. Barbier (Convenor ETF10) T. Wong (Convenor ETF11) U. Krischke (Convenor ETF 12) Mr. Bengt Jansson (Convenor CTL ETF 13) J. Hall (Convenor WG1) C. Swee-Gee (Convenor WG 3)</p> <p>R. Guirado (Convenor WG 5)</p>		
CTL-WG 5 “Software Evaluation”	CTL	<p>Convenor of the Technical Panel: Rafael GUIRADO – LCOE & Member of TC 61 Members of the Technical Panel: Masahiro SATO – JET & Convenor of IECEE CTL ETF 1 & Member of TC 61 Bernd GEHRKE – TC 61 & Chairman MT 23 Dieter FIETZ – TUV SUD Thomas Maier - UL (Demko) Markus Graedler - ZF Electronics GmbH Juan Carlos MOLINA MORENO – LCOE Bernhard SCHAEFERS – TUV SUD Maurizio FALORNI – IMQ Eckhard SCHWENDEMANN - ES-TMC Ralf Schwab - VDE Anton Rothuis - DEKRA Certification B.V.</p>	<ul style="list-style-type: none"> • To establish a consensus with methods acceptable to determine compliance with Annex R of IEC 60335-1 and Annex H of IEC 60730-1 • To develop a Guideline document & Work Instruction for testing purposes on how to implement the Annex R of IEC 60335-1 and Annex H of IEC 60730-1 • To develop a Checklist aiming at assisting Household Appliances Industry, Official Authorities and Stakeholders in the global market, Testing Laboratories and Certification Bodies to inform the latter with the testing procedures that are going to be applied related to the requirements as specified in 	



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
			<p>Annex R of IEC 60335-1 and Annex H of IEC 60730-1.</p> <ul style="list-style-type: none"> To develop an addendum to the TRF IEC 60335 series to cover the overall requirements pertaining to Annex R of IEC 60335-1 and Annex H of IEC 60730-1. This task will be undertaken by the IECEE WG 9 Test Report Forms however the direct input of the Technical Panel "Software Evaluation" is recommended. To set up the content of possible trainings for NCBS/CBTLs- Manufacturers-IECEE Technical Assessors to cover Software Evaluation issues. To be the IECEE Advisory Group on common understanding of Annex R of IEC 60335-1 and Annex H of IEC 60730-1 	
TASK FORCE 1	CTL	<p>M. Sato (Convenor) G. Camiciotti (IMQ) Technical Advisor J.D. Gonzales (IRAM) K. Wilson (Wakefield Labs) T. Lornitzo (OVE) F. Rosenberger (OVE) G. Tarseos (CSA) Z. Jurda (EZU) G. Bukkjaer (UL (Demko)) O. Väyrynen (FIMKO) A. Barrere (LCIE) B. Poesl (TÜV Rheinland LGA Products GmbH - DE) M. Hingott (TÜV PS) D. Fietz (TÜV PS) R. Gottschling (VDE) Z. Zsákai (TÜV Rheinland InterCert Kft., MEEI Division) J. Sumiya (JET)</p>	Household and similar equipment (HOUS) Portable tools (TOOL) and TOYS	On Going



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
		A. Sasaki (JQA) D. van Aalderen (DEKRA CERTIFICATION B.V.) T. Ulsrud (NEMKO) E. Cardoso (IEP) E.G. Chia (PSB) M. Zontar (SIQ) R. Guirado (LCOE) L. Mattson (SEMKO) R. Slupinski (UL (US)) J. Stimitz (UL (US)) L. Huang (Intertek Guangzhou) K. Park (KTL) A. Renn (TUV Rheinland HK) Y.G. Kong (KTL) J. Santos (CERTIF - PT) J.W. Byun (KTC) S. Ferrari (IMQ) C. Maes (SGS CEBEC) X. Zhou (CQC)		
TASK FORCE 2	CTL	M. Hingott (TUV SUD PS) (Convenor) M. Andersen (NEMKO) Technical Advisor IEC 60065 & IEC 60950 T. Burke (UL) Technical Advisor IEC 60950 T. Shiota (JQA) Technical Advisor IEC 60065 & IEC 60950 K. Wilson (UL International New Zealand) J.D. Gonzales (IRAM) T. Thun (TGM-VAE) X. Xiao (CQC) F. Homolka (EZU) J. J. Jensen (UL (Demko)) T. Silonsaari (FIMKO) J. Lanzo (LCIE) H. Frerk (VDE) A. Arndt (TÜV Rheinland) K.-H. Gompf (VDE) I. Seres (TÜV Rheinland InterCert Kft., MEEI Division) B. Burek (SGS Cebec) R. Yazaki (JET) J. Ologbosere (TUV Rheinland Japan) Jin-Soo Kim (KTL) A. Bergervoet (DEKRA CERTIFICATION B.V.) M. Ng (PSB)	Electronics and entertainment (TRON) IT and office equipment (OFF)	On Going



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
		M. Kiselja (SIQ) B. Jansson (SEMKO) P. Cross (NEMKO) D. Bras (EMITECH) V.K. Truong (Electrosuisse) C. Sato (UL (US)) Y-S Lee (KTC) B Lowe (CSA International) E. Yap (CSA International) G. Belussi (IMQ) W. Jäger (VDE) H. Kreuzer (VDE) J. Kellermeier (Mikes-Testingpartners Gmbh) R. Wunderer (OVE) I. Cohen (ITL)		
TASK FORCE 3	CTL	T. Gaertner (Convenor) R. A. Wunderer (OPFZ) A. Parzer (TÜV-A) J. Lanzo (LCIE) O. A. Nielsen (UL (Demko)) Mentula (SGS FIMKO) M. Sippl (TUV PS, Convenor SC 62AWG 14 - Liaison Officer) D. Fietz (TUV PS) L. Freudenreich (TÜV Rheinland) V. Ebinghaus (TÜV Rheinland) R. Schoensteiner (LGA) I. Seres (TÜV Rheinland InterCert Kft., MEEI Division) M. De Angiolini (IMQ) M. Kiselja (SIQ) P. Lymeus (SEMKO) V.K. Truong (Electrosuisse) G. Hines (ITS T&C) J. Murnane (UL (US)) S. Poutissou (CSA) M. Brossoit (CSA) B. Burek (SGS Cebec) Andreas Nilsson (Nemko A.S.) J. Metter (ETI) S. Seda (ETI) M. Strege (TUV RH JP) M. Bothe (VDE)	Electrical equipment for medical use (MED) Measuring equipment (MEAS)	On Going



IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
TASK FORCE 4	CTL	Andreas Bretz (VDE) (Convenor) H. Bachl (CTI) Technical Advisor M. Casari (IMQ) Technical Advisor B. B. Doyeo (IRAM) G. Miscovich (IRAM) C. Prochaska (TGM-VAE) S. Piras (SGS CEBEC) W. Zhang (CQC) M. Sobeslavsky (EZU) Lars T. Hansen (UL (Demko)) S. Lokfors (FIMKO) P. Balaire (ASTABEAB) P. Nagy (TÜV Rheinland InterCert Kft., MEEI Division) M. Casari (IMQ) K. Hasegawa (JET) Sung-Hee Mo (KTL) H. Barends (DEKRA CERTIFICATION B.V.) R. Hendriksen (DEKRA CERTIFICATION B.V.) J. Costa (ISQ) J. Santos (CERTIF) E. Venek (SIQ) T. de Frutos (AENOR) M. Huber (Electrosuisse) C.S. Kurten (UL (US)) J.S. Antony (UL (US)) Y. Liu (CQC) J.K. Park (KTL) G. Belussi (IMQ) J. Estelli (Intertek Semko AB)	Installation accessories and connecting devices (INST) Switches for appliances and automatic controls for electrical household appliances (CONT) Capacitors as components (CAP) MISC	On Going
TASK FORCE 5	CTL	E. Parma (Convenor) P. Kaufmann (VDE) Technical Advisor A.D. Hughes (Thorn Lighting Ltd. - Expert from Industry) Technical Advisor B. B. Doyeo (IRAM) G. Miscovich (IRAM) C. Prochaska (TGM-VAEE) R. Stoegmuller (OVE) S. Chen (CQC) F. Jandura (EZU) G. Bukkjaer (UL (Demko)) W. Parmiani (UL International Italia) P. U. K. Orrevetelainen (SGS FIMKO) M. Lescure(LCIE) D. Fietz (TUV SUD PS) H. Kilb (VDE)	Lighting (LITE) Safety transformers and similar equipment (SAFE)	On Going



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
		W. Menger (VDE) M. Kato (JET) S. J. UK (KTL) H. Telindert (DEKRA CERTIFICATION B.V.) T. Drost (DEKRA CERTIFICATION B.V.) E. Venek (SIQ) A. Valladolid (LCOE) Mr. N. Busby (L.A.L.) Ms. A. Branco (CERTIF) H.-K. Tan (TUV SUD PSB) F. Tironi (FLOS - Expert from Industry) T. Andersson (SEMKO) M. Stalder (Electrosuisse) C. Maes (SGS CEBEC) S. Shen (LCIE China) R. Mantegazza (MQ) P. Painini (IMQ) P. Jong Koo (KTL) P. Bacurik (EVPU) G. Klinger (TÜV Rheinland) E. Yap (CSA International) F. Rusnati (Assil) D. Lenasi (CSA International) J. Costa (ISQ) E. Cardoso (IEP) G. Del Amo Martinez (AENOR) T. Haupt (TÜV Rheinland LGA Products gmbh) D. Safiye (TSE) G. Göker (TSE)		
TASK FORCE 6	CTL	Zhu (TICW –Convenor) I. Mcguinnes (BSI) Technical Advisor J. Tuma (EZU) S. Lokfors (FIMKO) C. Mazzucchi (IMQ) O.A. Nielsen (UL (Demko)) G. Mackenbach (DEKRA CERTIFICATION B.V.) F. Shirai (JET) Hoowo Kang (KTL) A.C. Figueiral (CERTIF) J.M. Cruz (ISQ) H. Chuan Wee (PSB) T. Kokelj (SIQ) N. Tjapkin (GAMA) A. Benelli (IMQ)	Cables and cords (CABL)	On Going
TASK FORCE 7	CTL	Mr. Bachl (CTI) - Convenor ad interim S. Piras (SGS CEBEC)	Low voltage high power switching equipment installation (POW)	On Going



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
		M. Sobeslavsky (EZU) V. Fiederichs (International Product Safety GmbH) J.-F. Bruel (LCIE) S. Lautamies (FIMKO) A. Bretz (VDE) P. Nagy (TÜV Rheinland InterCert Kft., MEEI Division) M. Casari (IMQ) S.P. Ahn (KERI) H. Kormelink (DEKRA CERTIFICATION B.V.) A. Orte (AENOR) D. Mueller (UL (US)) J. Estelli (Intertek Semko AB)	Protective equipment (PROT)	
TASK FORCE 8	CTL	D.W. O'Shea (Convenor) L.T. Hansen (UL (Demko)) N. Nakamura (JET) T. Yamada (JQA) N. Tjapkin (GAMMA)	Plastics	Disbanded during the CTL meeting in Johannesburg 2006-04-18
TASK FORCE 9	CTL	L. Ji (UL Inc.) -Convenor A. Roth (VDE) J. H. Wohlgemuth (NREL) N. Wilmot (Murdoch University) Y. Murakami (JET) H. Barikmo (TC82) W. Kang (CQC) S. Wu (Intertek Taiwan) C. Hee (Intertek Singapore) C. Roversi (IMQ S.p.A.) S. Poutissou (CSA International) G. Bellenda (Eurofins) M. Szentpaly (TÜV Rheinland InterCert Kft., MEEI Division) C. Flueckiger (UL (US)) J. Althaus (TUV Rheinland) R. Arndt (TUV SUD America)	Photovoltaics	On Going



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
TASK FORCE 10	CTL	<p>(- Convenor) B. Berglof (Intertek Semko) D. Rivoltella (Sicur Control) J. Zheng (CQC) K.W. Friedrich (TUV Rheinland) J. Nyman (Nemko) S. Kloska (VDE) A. Van Der Meijden (DEKRA CERTIFICATION B.V.) H. Yamashita (JET) S.-J. Kim (KTL) J. Merikari (SGS Fimko) T. Hada (JQA) C. Cantaluppi (IMQ) G. Gamperi (TGM-VAEE) R. Guirado (LCOE) B. Delisi (UL (US)) C. Hauser (Electrosuisse) M. Mak (SIQ) J. Deng (TUV SUD PSB) J. Merikari (SGS FIMKO) Y. Litvinov (Intertek) R. Colombo (IMQ) S. Legros (LCIE - Bureau Veritas)</p>	Electromagnetic Compatibility	On Going
TASK FORCE 11	CTL	<p>T. Wong (CSA International) Convenor N. Stoev (CSA International) Technical Advisor R. Wunderer (OVE) K. Tachihara (JQA) Chul-Joo Jeon (KTL) A. Bergervoet (DEKRA CERTIFICATION B.V.) M. Kiselja (SIQ) B. Jansson (SEMKO) V.K. Truong (Electrosuisse) I. Antonov (SII) P. Boden (UL (US)) V. Ebinghaus (TUV RH DE) A. Roth (VDE) V. Kalakutskiy (TUV RH JP) O. Stilling (Intertek Semko Shanghai) Y. E. Teong (TUV SUD PSB) K.J. Puckett (TUV SUD PS) M. H. Han (KTC) E. Franchina (IMQ S.p.A.) Y. Liu (ITS NA)</p>	Lasers	



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
TASK FORCE 12	CTL	Dr. U. Krischke (SGS-Germany) Convenor J. Han (SGS- Korea) A. Maijala (SGS- Finland) C. Chu (SGS- Taiwan) G. Fong (SGS- Taiwan) K. Goto (SGS- Japan) S. MacLeod (UL (US)) M. Jahns (TUV SUD) H. Hinrichs (Bureau Veritas Consumers Product Services GmbH) M. Cheng (Nemko Shanghai) C. List (Intertek Consumer Goods GmbH) T. Ernst (VDE) D. Elks (Intertek) N. Sözer Güllü (Intertek Testing Services Turkey) P. Spengler (DEKRA Industrial GmbH)	Hazardous Substances	
TASK FORCE 13	CTL	Bengt Jansson (Intertek Semko AB) - Convenor Laurie Florence (UL (US)) Hyun-Jong Jun (KTL) Saadia Jebnoun (LCIE Bureau Veritas) Jean Lanzo (LCIE Bureau Veritas) Kun-Jeng Liang (UL Taiwan Co., Ltd.) Sammy Wu Wu (Intertek Taiwan) Raymond Zhou (Intertek China) Jody Leber (SGS) Timo Silonsaari (SGS Fimko) Szecsei (TÜV Rheinland InterCert Kft., MEEI Division) C. Swee-Gee (TUV SUD PSB)		

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IEC CAB TECHNICAL PANEL

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
IEC-CAB TECHNICAL PANEL		Mr. P. de Ruvo (Convenor) Mr. D. Mader (UL Inc.) Mr. J. Gryn (UL (CA)) Mr. C. Agius (IECEX) Mr. U. Klausmeyer (Observer) Mr. N. Mueller (?) Mr. J. Hattingh (?) Mr. J. Mitchell (?) Mr. C. Watson (?) Ms. M. Malmqvist (SWEDAC)		

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JWG – JOINT WORKING GROUP

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
JWG “COMMON UNDERSTANDING OF ISO/IEC 17025”		Mr. de Ruvo (Convenor) Mr. A. Pederneschi (IMQ) Mr. D. Mader (UL Inc.) Mr. J. Gryn (UL (CA)) Mr. J. Xie (CNCA) Mr. W. Kreinberg (TUV PS) Mr. M. Wittner (IRAM) Mr. T. Sollie (NEMKO) Mr. G. Dreger (VDE) Mr. C. Agius (IECEX) Mr. U. Klausmeyer (IECEX) Mr. N. Mueller (?) Mr. J. Hattingh (?) Mr. S. Sydney (?) Mr. J. Mitchell (?) Mr. C. Bestwick (UKAS) Mr. C. Watson (?) Mr. L. Bauder (METAS) Ms. M. Malmqvist (SWEDAC)		

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